

GaN 650V GaN HEMT

RC65D600C

Description

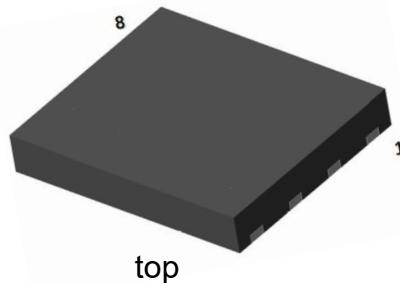
The RC65D600C Series 650V, 600mΩ gallium nitride (GaN) FETs are normally-off devices.

RealChip GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic on-resistance, delivering significant advantages over traditional silicon (Si) devices.

RealChip is a leading-edge wide band gap supplier with world-class innovation .

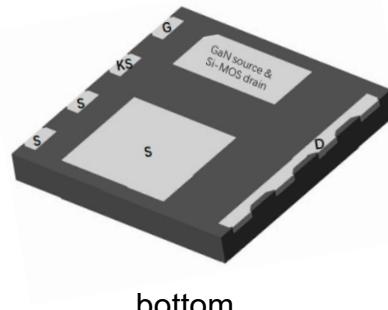
Ordering Information

Part Number	Package	Package Configuration
RC65D600C	DFN5*6	Source

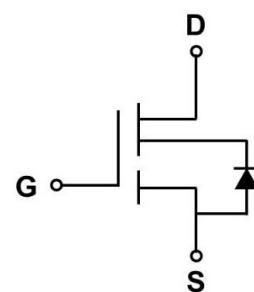


Application

- Adapter
- Renewable energy
- Telecom and data-com
- Servo motors
- Industrial
- Automotive



bottom



Circuit Symbol

General Features

Easy to drive—compatible with standard gate drivers

Low conduction and switching losses

RoHS compliant and Halogen-free

Benefits

Increased efficiency through fast switching

Increased power density

Reduced system size and weight

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	600mΩ	4.8A	8nC

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Absolute Maximum Ratings

$T_c=25^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Limit value	Unit
V_{DSS}	Drain to source voltage ($T_j = -55^\circ\text{C}$ to 150°C)	650	
$V_{(\text{TR})DSS}$	Drain to source voltage-transient ^a	800	V
V_{GSS}	Gate to source voltage	-20~+20	
I_D	Continuous drain current @ $T_c=25^\circ\text{C}$ ^b	4.8	A
	Continuous drain current @ $T_c=125^\circ\text{C}$ ^b	2.1	
I_{DM}	Pulse drain current (pulse width: 10μs)	8	A
P_D	Maximum power dissipation @ $T_c=25^\circ\text{C}$	33	W
T_c	Operating temperature	Case	${}^\circ\text{C}$
T_j		Junction	${}^\circ\text{C}$
T_s	Storage temperature	-55~150	${}^\circ\text{C}$

a. In off-state, spike duty cycle D<0.01, spike duration <1μs

b. For increased stability at high current operation

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Thermal Resistance

Symbol	Parameter	Limit value	Unit
$R_{\theta JC}$	Junction-to-case	3.7	°C /W

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Electrical Parameters

T_j=25°C unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
V _{(BL)DSS}	Drain-source voltage	650	-	-	V	V _{GS} = 0V
V _{GS(th)}	Gate threshold voltage	3.3	3.9	4.5	V	
ΔV _{GS(th)/T_J}	temperature coefficient	-	-7	-	mV/°C	V _{DS} =1V, I _{DS} =1mA
R _{DS(on)}	Drain-source on-Resistance	-	600	720	mΩ	V _{GS} =10V, I _D =1A, T _J =25°C
		-	1260	-		V _{GS} =10V, I _D =1A, T _J =150°C
I _{DSS}	Drain-to-source leakage current	-	1	10	μA	V _{DS} =650V, V _{GS} = 0V, T _J =25°C
		-	5	100		V _{DS} =650V, V _{GS} = 0V, T _J =150°C
I _{GSS}	Gate-to-source forward leakage current	-	-	±100	nA	V _{GS} =±20V
C _{ISS}	Input capacitance	-	331	-		
C _{OSS}	Output capacitance	-	11	-	pF	V _{GS} =0V, V _{DS} =400V, f=1MHz
C _{RSS}	Reverse capacitance	-	1.2	-		
Q _G	Total gate charge	-	8	-		
Q _{GS}	Gate-source charge	-	1.7	-	nC	V _{DS} =400V, V _{GS} =0V to 10V, I _D =1A
Q _{GD}	Gate-drain charge	-	4	-		
Q _{OSS}	Output charge	-	14	-	nC	V _{GS} =0V, V _{DS} =0V to 400V, f=1MHz
t _{D(on)}	Turn-on delay	-	3.2	-		
t _R	Rise time	-	5.5	-	ns	V _{DS} =400V, V _{GS} =0V to 10V, I _D =2.1A, R _{G-on(ext)} =6.8Ω, R _{G-off(ext)} =2.2Ω, L=250μH
t _{D(off)}	Turn-off delay	-	7.4	-		
t _F	Fall time	-	27	-		

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Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V _{SD}	Source-Drain reverse voltage	-	2.3	-	V	V _{GS} =0V, I _{SD} =2.5A
t _{RR}	Reverse recovery time	-	14	-	ns	
Q _{RR}	Reverse recovery charge	-	6.5	-	nC	I _F =2.5A, V _{DD} =400V, dI _F /dt=165A/μs

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Typical Characteristics

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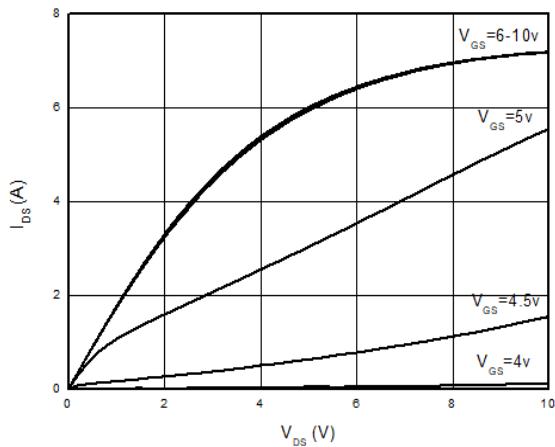


Figure 1. Typical Output Characteristics $T_j=25^\circ\text{C}$

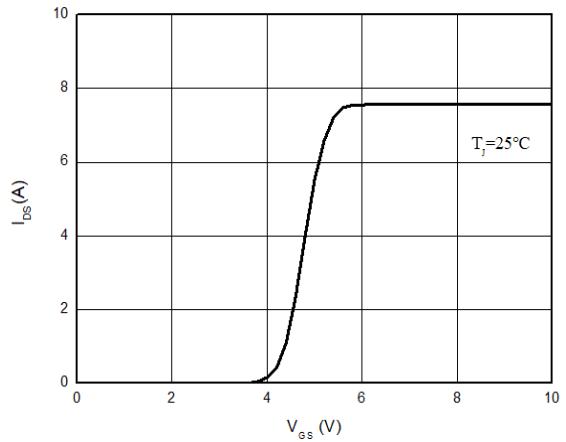


Figure 2. Typical Transfer Characteristics ($V_{DS}=10\text{V}$)

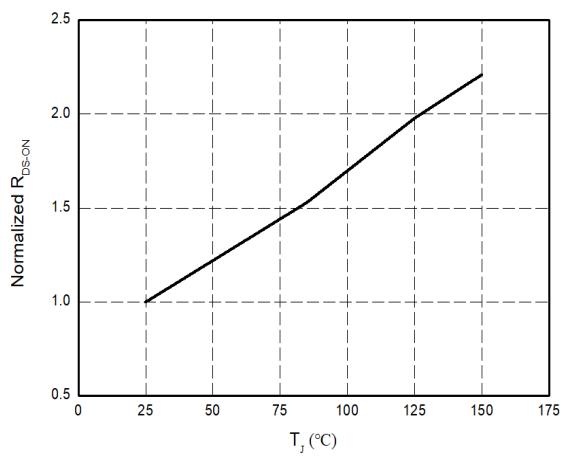


Figure 3. Normalized On-resistance

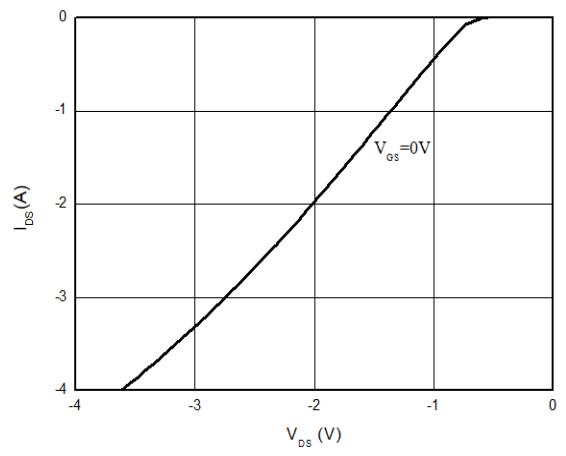


Figure 4. Channel Reverse Characteristics $T_j=25^\circ\text{C}$

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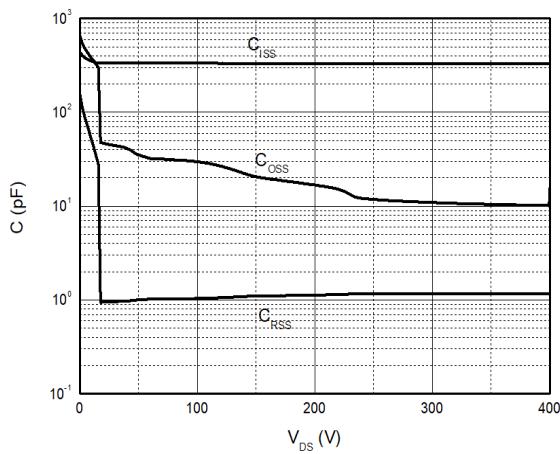


Figure 5. Typical Capacitance ($f=1\text{MHz}$)

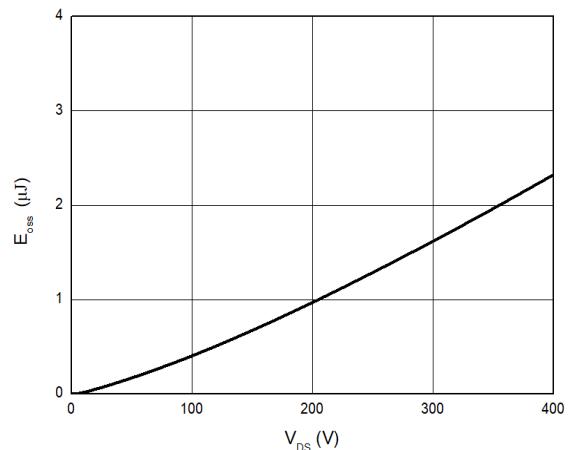


Figure 6. Typical C_{oss} Stored Energy

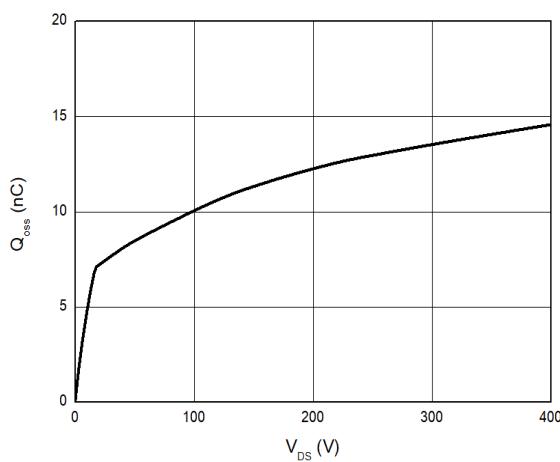


Figure 7. Typical Q_{oss}

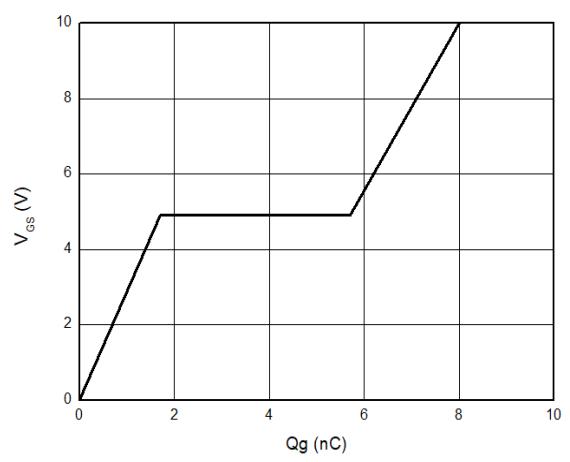


Figure 8. Typical Gate Charge ($V_{DS}=400\text{V}$, $I_D=1\text{A}$)

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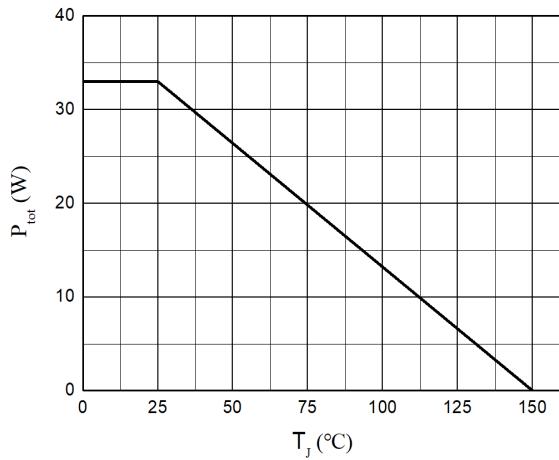


Figure 9. Power Dissipation

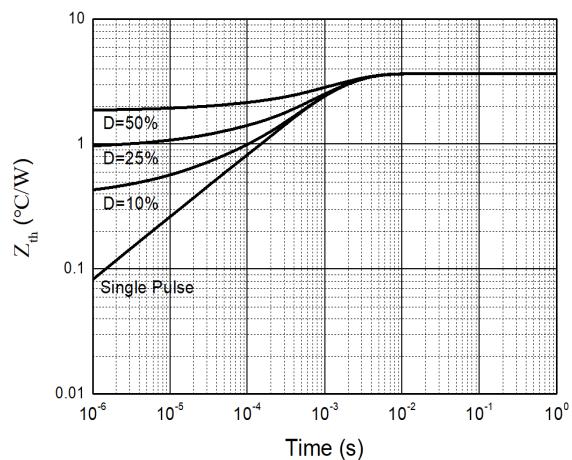


Figure 10. Transient Thermal Resistance

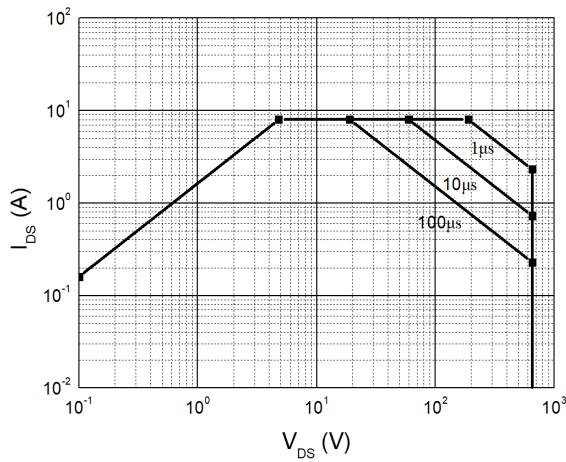


Figure 11. Safe Operating Area $T_j=25^\circ\text{C}$

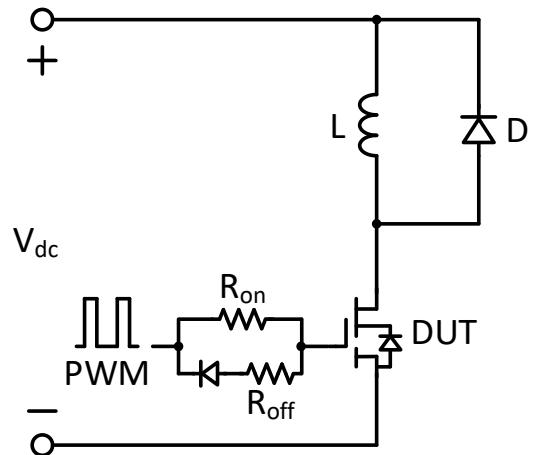


Figure 12 Switching times with inductive load

$V_{\text{DS}}=400\text{V}$, $V_{\text{GS}}=0\text{V}$ to 10V , $I_{\text{D}}=2.1\text{A}$,
 $R_{\text{G-on(ext)}}=6.8\Omega$, $R_{\text{G-off(ext)}}=2.2\Omega$, $L=250\mu\text{H}$

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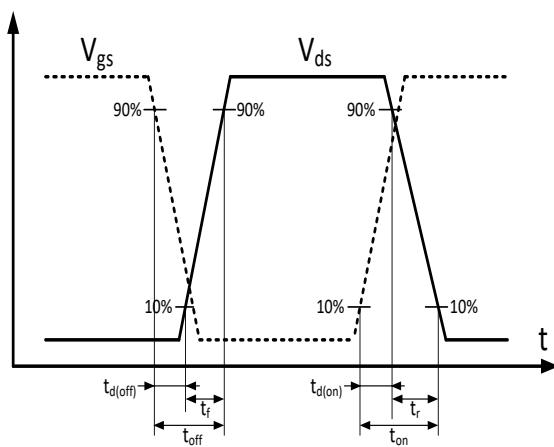


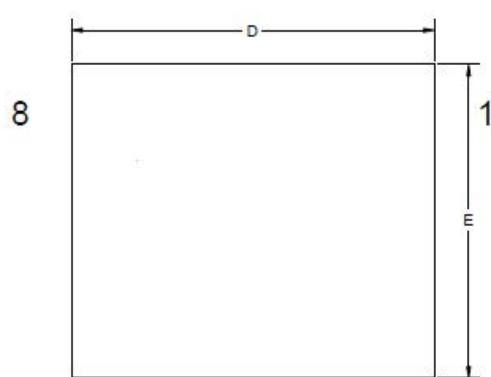
Figure 13. Switching times with waveform

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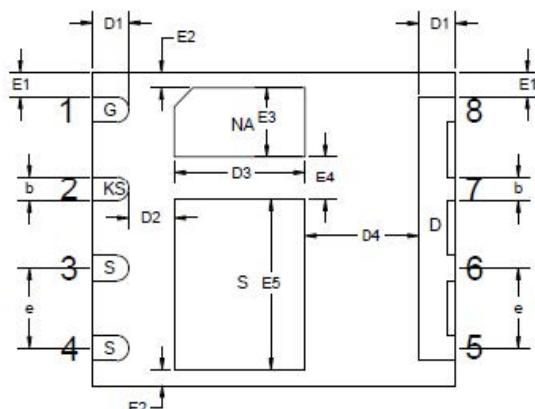
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PACKAGE DIMENSIONS

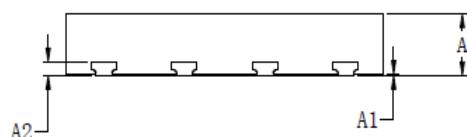
TOP VIEW



BOTTOM VIEW



Side View(left/right)



Symbol	Min. (mm)	Mean. (mm)	Max. (mm)
A	0.850	0.900	0.950
A1	0.000	0.020	0.050
A2		0.203REF	
D	5.900	6.000	6.100
E	4.900	5.000	5.100
D1	0.500	0.600	0.700
D2	0.650	0.750	0.850
D3	2.050	2.150	2.250
D4	1.800	1.900	2.000
E1	0.295	0.395	0.495
E2	0.195	0.295	0.395
E3	0.990	1.090	1.190
E4	0.600	0.700	0.800
E5	2.610	2.710	2.810
b	0.300	0.400	0.500
e	1.170	1.270	1.370